# Study of Proton Irradiation on InGaAs Photodiodes and Laserdiodes

#### Claire Garden / Ali Mohammadzadeh TOS-QCA



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#### **Introduction**

• Proton irradiation: affects device performances through displacement damage

- What parameters are affected?
- Understand the process causing these effects



#### **Electrical Parameters**

#### Photodiodes

• Laser diodes

I-V characteristic

Power versus the injected current

Dark current

Threshold current

- Photocurrent

Note: Measurements @ 20 °C



### **Predictions**

#### • Photodiodes

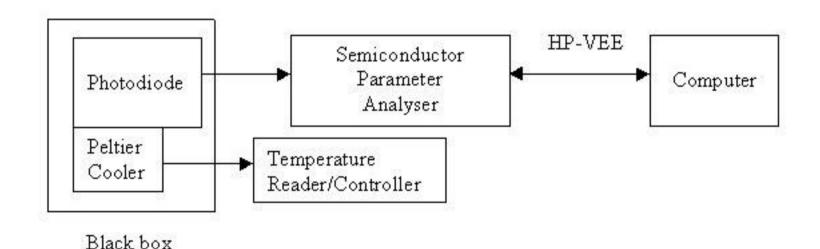
- Dark current ↑
- Photocurrent ↓
- I-V curve modified

#### Laser diodes

- Threshold current ↑
- Optical Power ↓



# Bench Set-up I-V Characteristic (PD)





#### **HP-VEE Program**

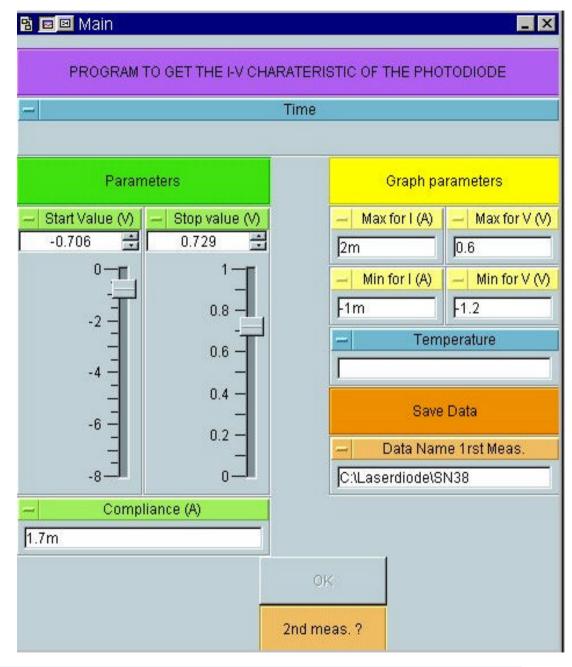
(Visual Engineering Environment)

- Instrument control
- Measurement processing
- Test reporting



### Example:

Graphical interface of I-V program





#### InGaAs devices

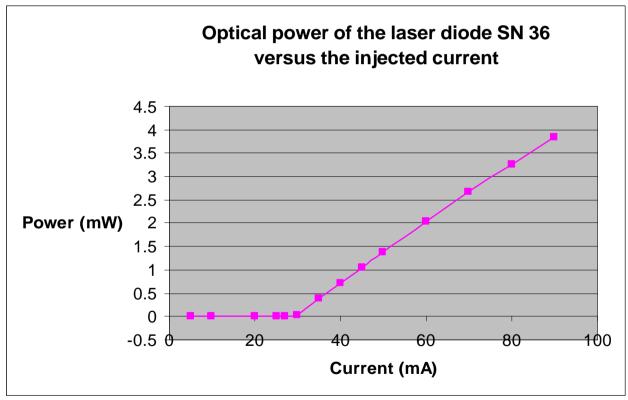
- MIPAS ODS project
  - 4 photodiodes
  - 2 laser diodes of 1.3
     μm wavelength

- THOMSON-CSF
  - 14 devices with active
     layer thickness of 3 μm
     and 6 μm
  - 2 MSG SEVIRI devices

 $\Rightarrow$  3 PDs / device = 48 PDs



## Typical Characteristic of MIPAS laser diode



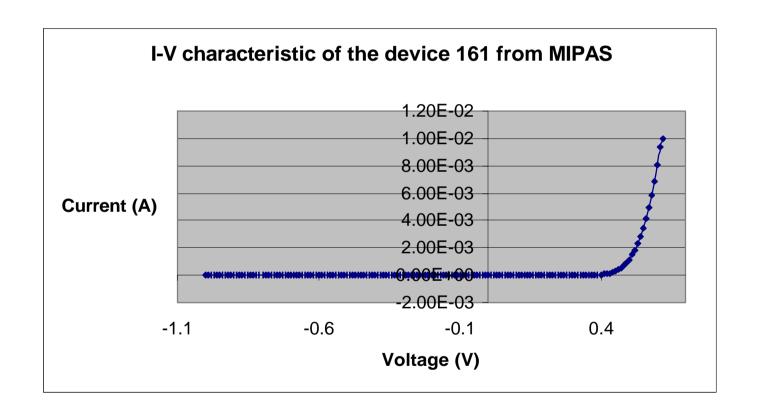


# Typical Values for the Threshold Current (MIPAS Laserdiodes)

Device Names	SN 27	SN 36
I threshold	28.27 mA	28.66 mA



## Typical I-V Characteristic





## Typical Value of Photocurrent MIPAS / THOMSON devices

		Photocurrent (A	A) at $V_R = 5V$				
	1	MIPAS and THO	MSON device	vices			
Wavelength	3 μm epitaxy layer	6 μm epitaxy layer	MSG SEVIRI	Sn243	Sn249		
700 nm	-1.91 e-7	-1.66 e-7	-1.46 e-7	-5.8 e-8	-6.7 e-8		
900 nm	-1.77 e-7	-1.65 e-7	-1.58 e-7	-8.68 e-8	-9.5 e-8		
1100nm	-3.12 e-7	-2.69 e-7	-3.11 e-7	-1.6 e-7	-1.66 e-7		
1300 nm	-4.37 e-7	-4 e-7	-4.26 e-7	-2.04 e-7	-2.08 e-7		



## Typical Values of Dark Current MIPAS / THOMSON devices

MIPAS and TH	OMSON devices	
6 μm epitaxy layer	MSG SEVIRI	Sn243
-0.095	-10.54	-0.124
	6 μm epitaxy layer	epitaxy layer



## Irradiation Test Plan MIPAS / THOMSON

	MIPAS		THOMSON		
	Photodiodes	Laserdiodes	Photodiodes		
	Fluence (p/cm <sup>2</sup> )				
ALDONO PATROAGONO	1 108	9915-000	1 10 <sup>9</sup>		
30 MeV	1 10 <sup>10</sup>	1 10 <sup>9</sup>	1 10 <sup>11</sup>		
2 MeV	1 1011	1 1011	1 10 <sup>8</sup>		
			1 10 <sup>10</sup>		
			1 1012		



### Conclusion

- Next steps:
  - Irradiation of devices
  - Electrical characterisations
  - Pre and post data analysis
  - Second run of irradiation

